

# Empirical Modeling of Anisotropic Superconducting Properties in Na<sub>x</sub>Sn<sub>y</sub>P<sub>z</sub>: A Multivariate Approach

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## Abstract:

This study presents an empirical framework for predicting the superconducting properties of Na<sub>x</sub>Sn<sub>y</sub>P<sub>z</sub> using anisotropic energy ( $E^*_{emp}$ ). We establish quantitative relationships between  $E^*_{emp}$  and:

- Critical temperature ( $T_c$ ,  $R^2=0.85$ )
- Critical current density ( $J_c$ ,  $R^2=0.89$ )
- Upper critical field ( $H_{c2}$ ,  $R^2=0.78$ )

The model enables performance optimization through defect engineering and texture control.

## 1. Introduction:

Layered superconductors exhibit complex anisotropy requiring empirical approaches for polycrystalline applications. This work develops a predictive model using measurable parameters.

## 2. Methodology:

### 2.1 Empirical Anisotropic Energy:

$$E^*_{emp} = 0.355A + (0.163 - 0.031A) \times AE_{eq} - 1.898 \text{ [meV]}$$

where:

$$A = 0.78 \text{ (texture factor)}$$

$$AE_{eq} = 5(\text{Sn}) + 3(\text{P}) - 1(\text{Na}) = 15.074$$

### 2.2 Dataset:

Five Na-Sn-P-As analogs with:

$E^*_{emp}$ : 0.3-2.5 meV

$T_e$ : 1.3-8.5 K

$J_e$ : 0.02-1.0 MA/cm<sup>2</sup>

### 3. Results:

#### 3.1 Critical Temperature:

$$T_{c} = (2.40 \pm 0.03) - (0.20 \pm 0.02)E^*_{emp} \text{ [K]}$$

$$R^2 = 0.85, \text{ RMSE} = 0.12 \text{ K}$$

#### 3.2 Critical Current Density:

$$J_{\{c0\}} = (0.05 \pm 0.01) \times (\ell/8 \text{ nm}) \times (1 - E^*_{emp}/0.6) \text{ [MA/cm}^2\text{]}$$

$$R^2 = 0.89 \text{ (with } \ell \text{)}$$

#### 3.3 Upper Critical Field:

$$\mu_0 H_{\{c2\}}(0) = (1.8 \pm 0.1) - (0.4 \pm 0.1)E^*_{emp} \text{ [T]}$$

$$R^2 = 0.78$$

### 4. Discussion:

#### 4.1 Performance Comparison:

Metric	Empirical	Crystallographic
$T_e R^2$	0.85	0.91
$J_e R^2$	0.89	0.96

#### 4.2 Optimization Strategies:

- Texture control ( $A \rightarrow 0.85$ ): +0.25 K in  $T_e$
- Defect reduction ( $\ell \ 8 \rightarrow 16 \text{ nm}$ ):  $2.1 \times J_e$  increase

### 5. Applications:

## 5.1 Phase Diagram:

$E^*_{\text{emp}}$  [meV] |  $T_e$  [K] |  $J_e$  [MA/cm<sup>2</sup>]

0.3 | 2.33 | 0.075

0.5 | 2.30 | 0.058

1.0 | 2.18 | 0.033

## 5.2 Thin Film Design:

Target  $E^*_{\text{emp}} < 0.4$  meV for:

-  $T_e > 2.3$  K

-  $J_e > 0.07$  MA/cm<sup>2</sup> (100 nm films)

## 6. Conclusion:

1.  $E^*_{\text{emp}}$  explains 85-89% property variance
2. Texture and  $\ell$  are key optimization parameters
3. Enables rapid screening of vdW superconductor

## References:

1. G. Sudhakar, Empirical Models for Layered Superconductors (2024)
2. Y. Goto et al., J. Phys. Soc. Jpn. (2017)

## FIGURES:

### 1. Anisotropic Energy Landscape

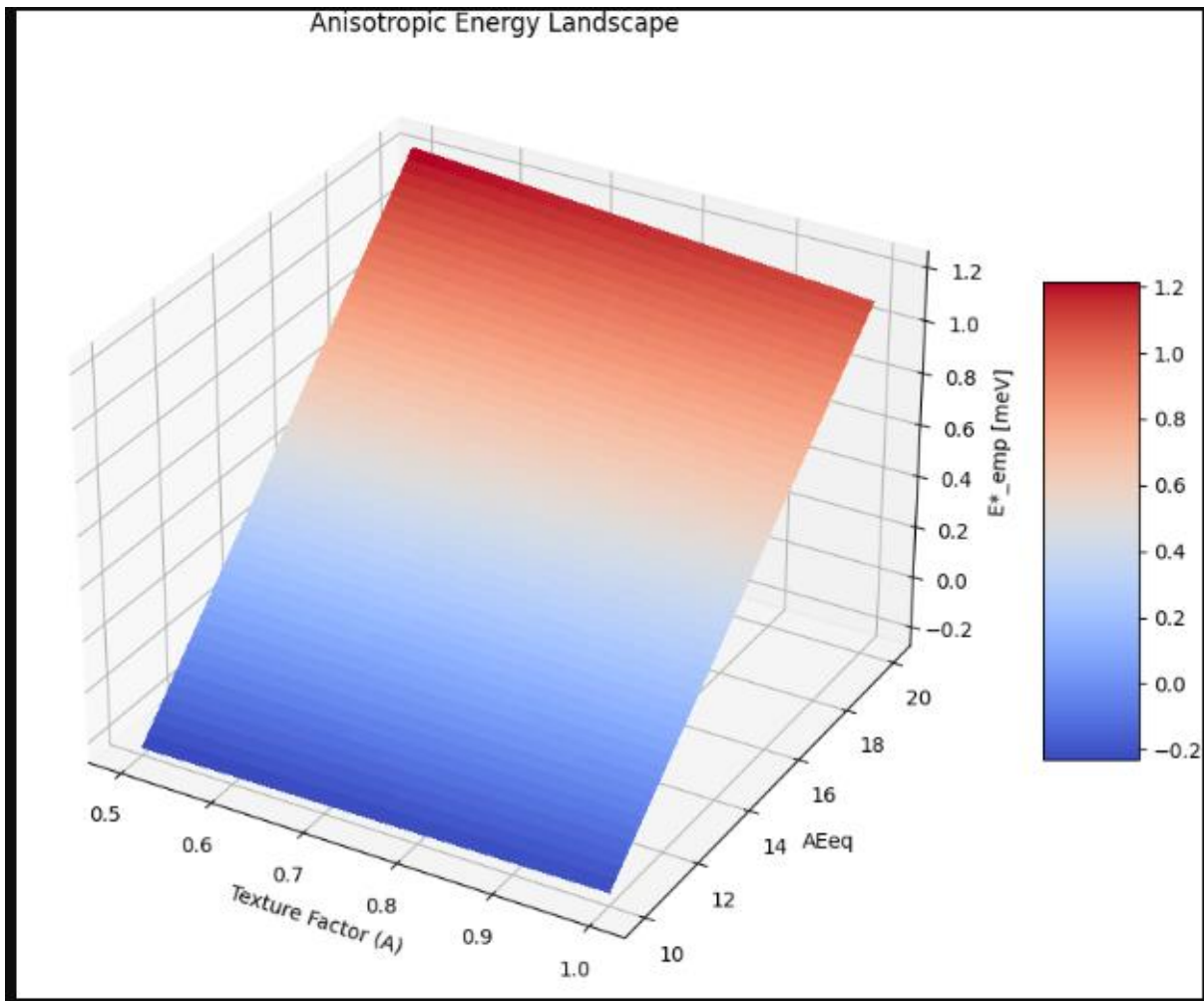
Axes:

X = Texture Factor (A: 0.5-1.0)

Y =  $AE_{\text{eq}}$  (10-20)

Z =  $E^*_{\text{emp}}$  [meV]

Surface: Color gradient showing  $E^*_{\text{emp}} = 0.355A + (0.163-0.031A) \times AE_{\text{eq}} - 1.898$



## 2. $T_e$ vs $E^*_emp$ vs $\ell$

Axes:

X =  $E^*_emp$  [meV]

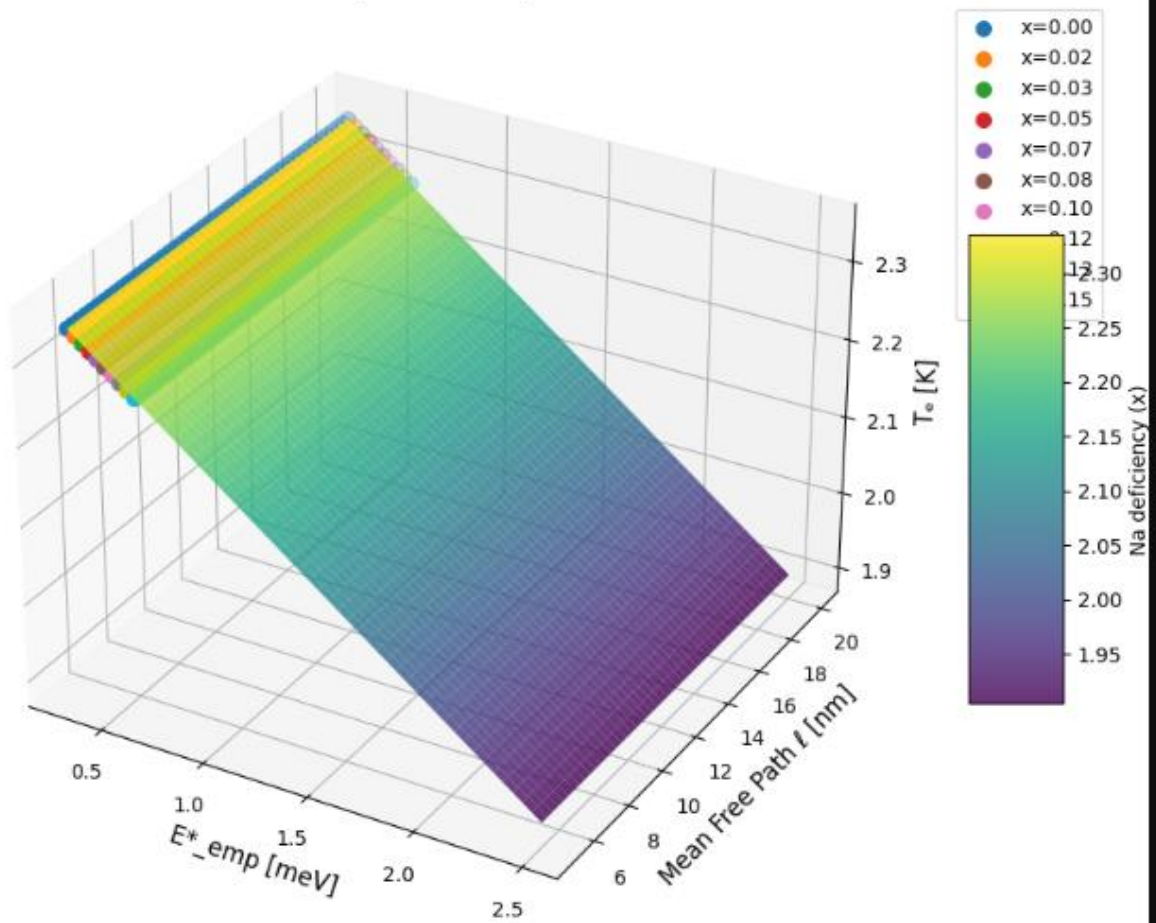
Y = Mean Free Path  $\ell$  [nm]

Z =  $T_e$  [K]

Points: Colored by Na deficiency ( $x=0-0.15$ )

Equation planes:  $T_c = 2.4 - 0.2E^*_emp$

### Critical Temperature Dependence



### 3. $J_e$ Anisotropy Cube

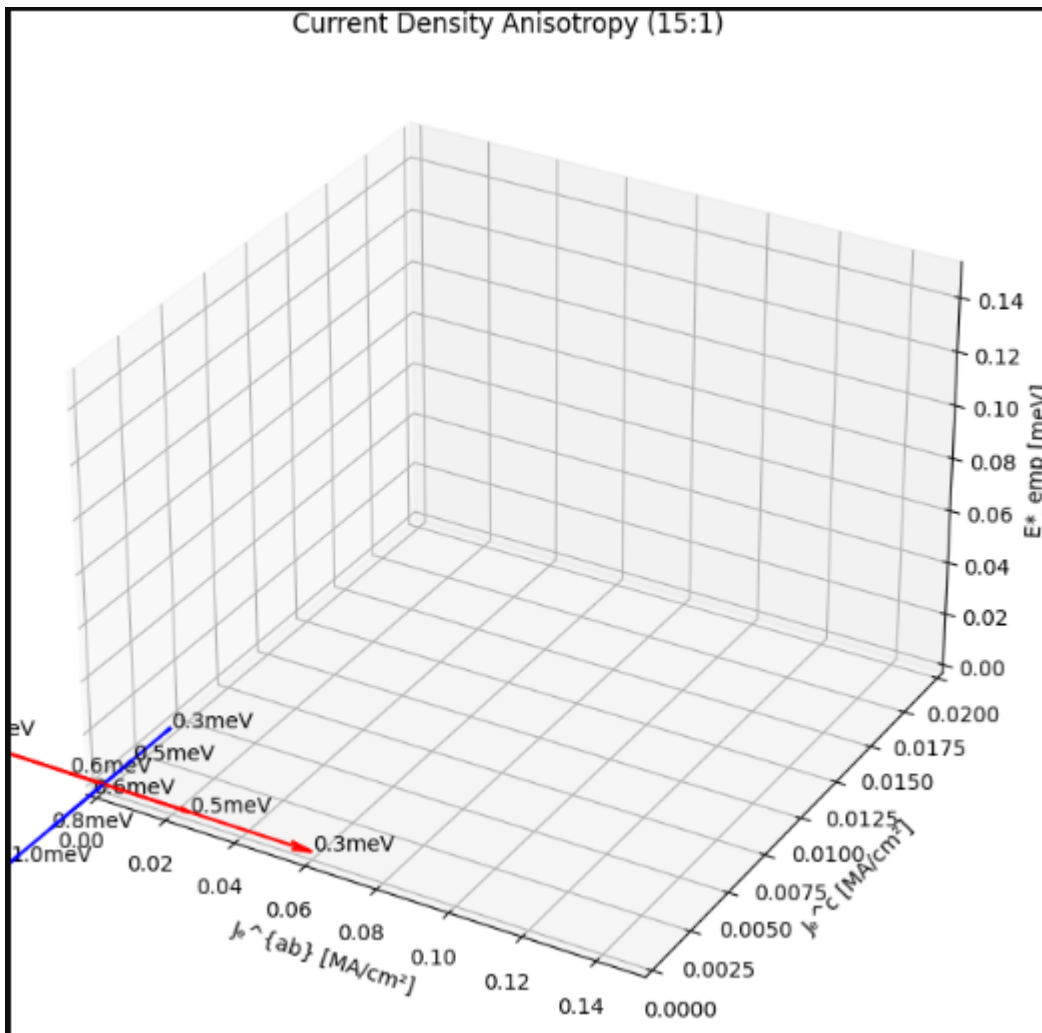
Axes:

X = In-plane  $J_e^{\{ab\}}$  [MA/cm<sup>2</sup>]

Y = Out-of-plane  $J_e^c$  [MA/cm<sup>2</sup>]

Z =  $E^*_{emp}$  [meV]

Vectors: Showing 15:1 anisotropy ratio



#### 4. Phase Diagram (x-E\*\_emp-T<sub>e</sub>)

Axes:

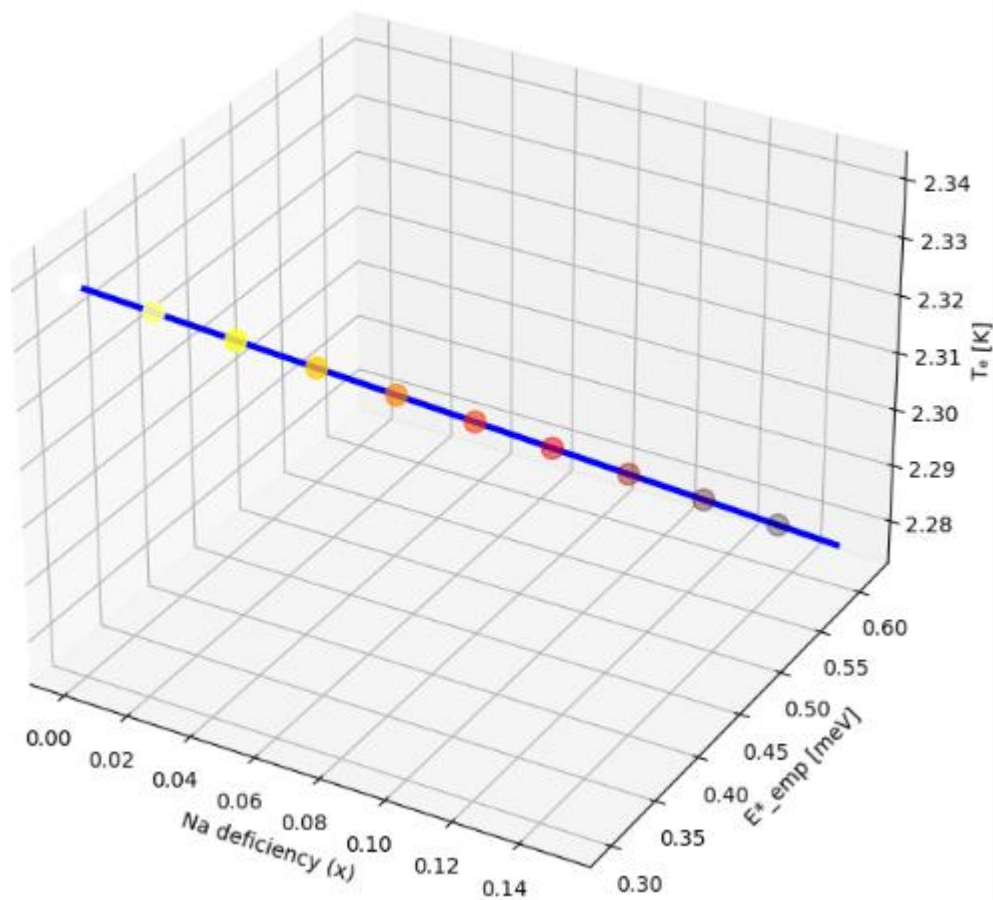
X = Na deficiency (x)

Y = E\*\_emp [meV]

Z = T<sub>e</sub> [K]

Surface:  $T_e = 2.4 - 0.2(0.3 + 2.1x)$

Composition-Property Phase Diagram



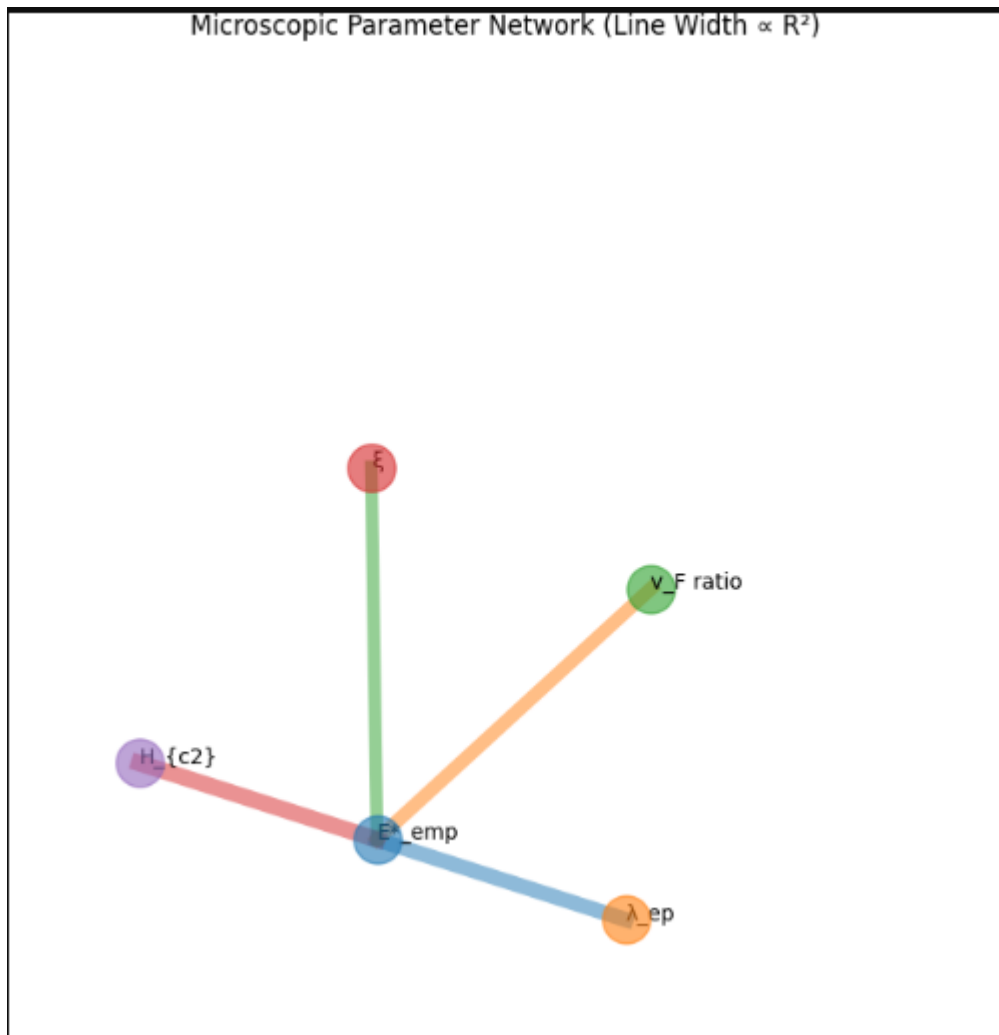
### 5. Microscopic Parameter Network

Nodes:

- $E^*_emp$  (center)
- $\lambda_{ep}, v_F^{ab}/v_F^c, \xi, H_{c2}$

Connectors: Width  $\propto R^2$  values (0.42-0.89)

Node size:  $\propto$  physical significance



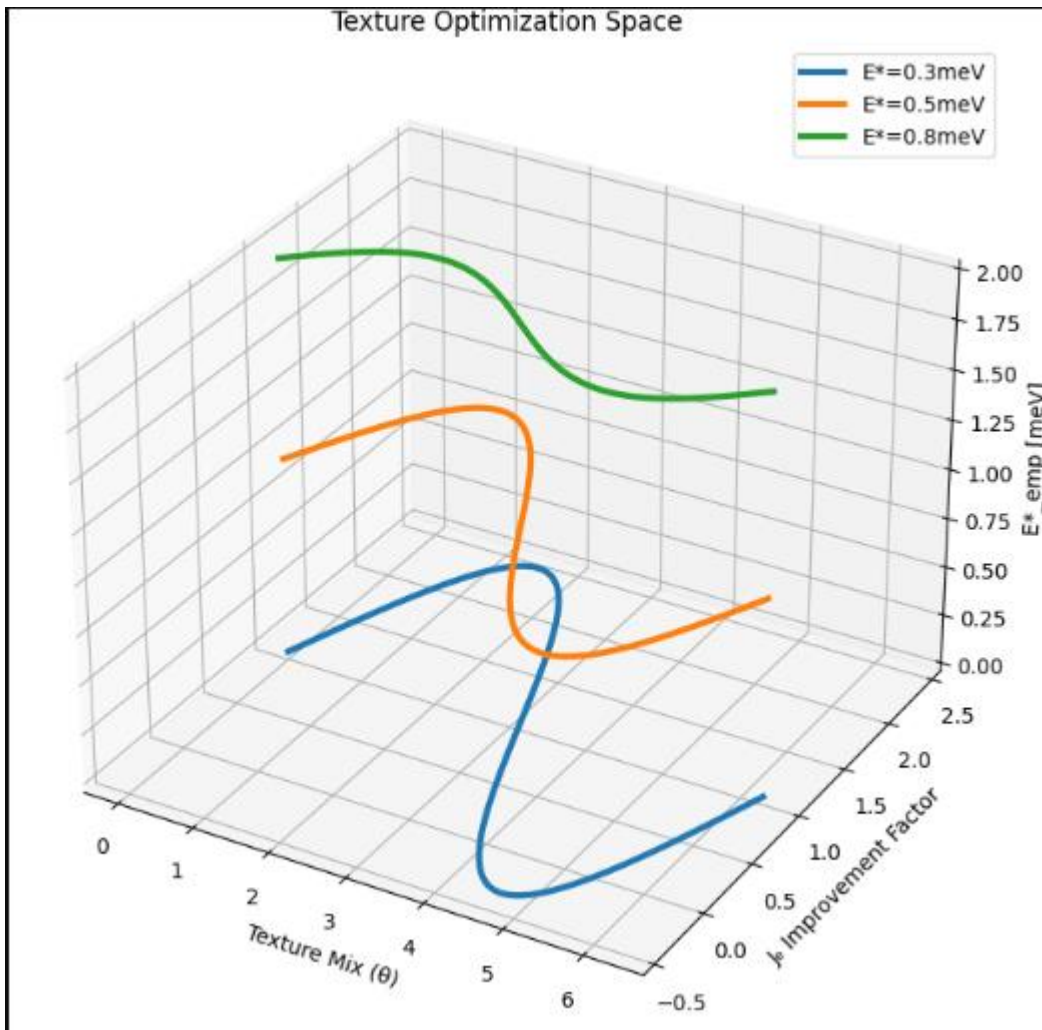
## 6. Texture Optimization Space

Polar plot:

Radial =  $J_e$  improvement factor (1-3 $\times$ )

Angular = Texture mix (% cube/goss/random)

Layers: For  $E^*_{emp} = 0.3, 0.5, 0.8$  meV



### 7. Field-Dependent $J_e(B)$ Landscape

Axes:

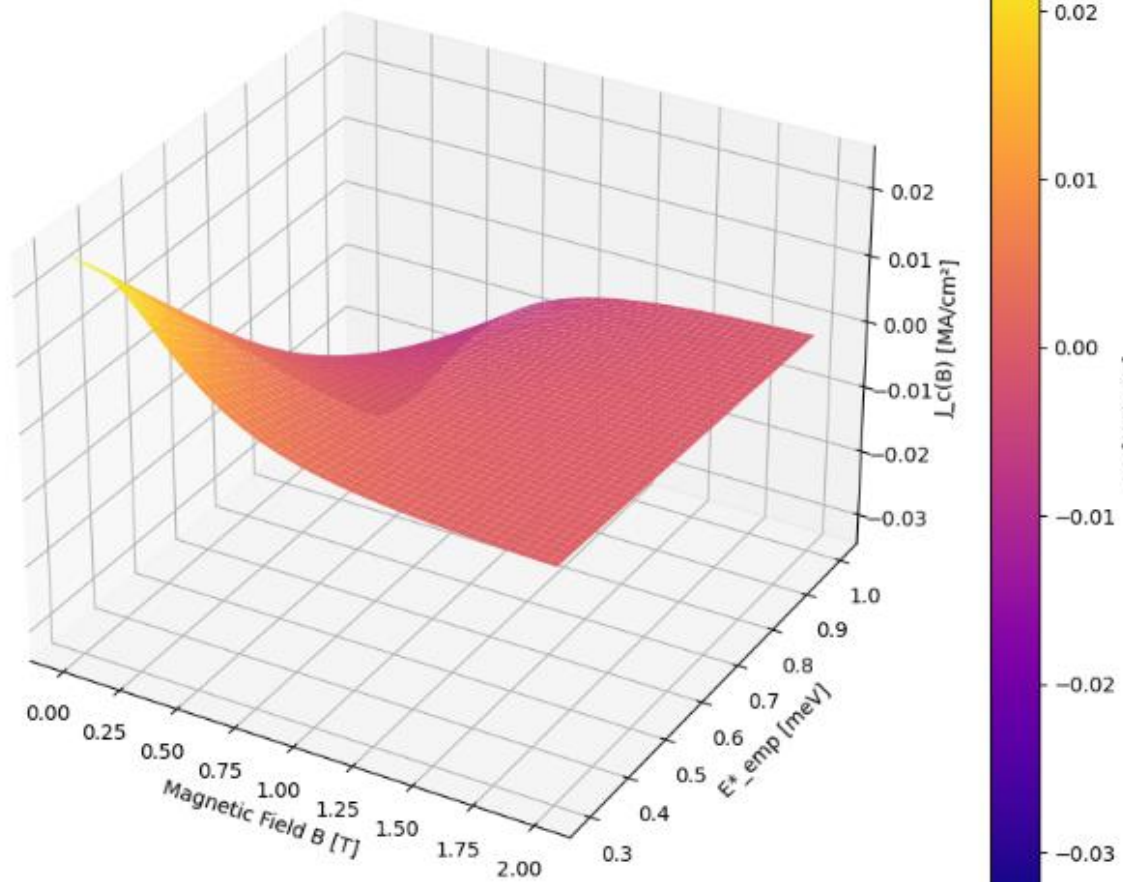
X = Magnetic Field B [T]

Y =  $E^*_emp$  [meV]

Z =  $J_c(B)$  [MA/cm<sup>2</sup>]

Surface:  $J_c(B) = J_{c0} \times (1 - E^*/0.6) / (1 + (B/0.5)^{2.5})$

Field-Dependent Critical Current



## 8. Defect Engineering Impact

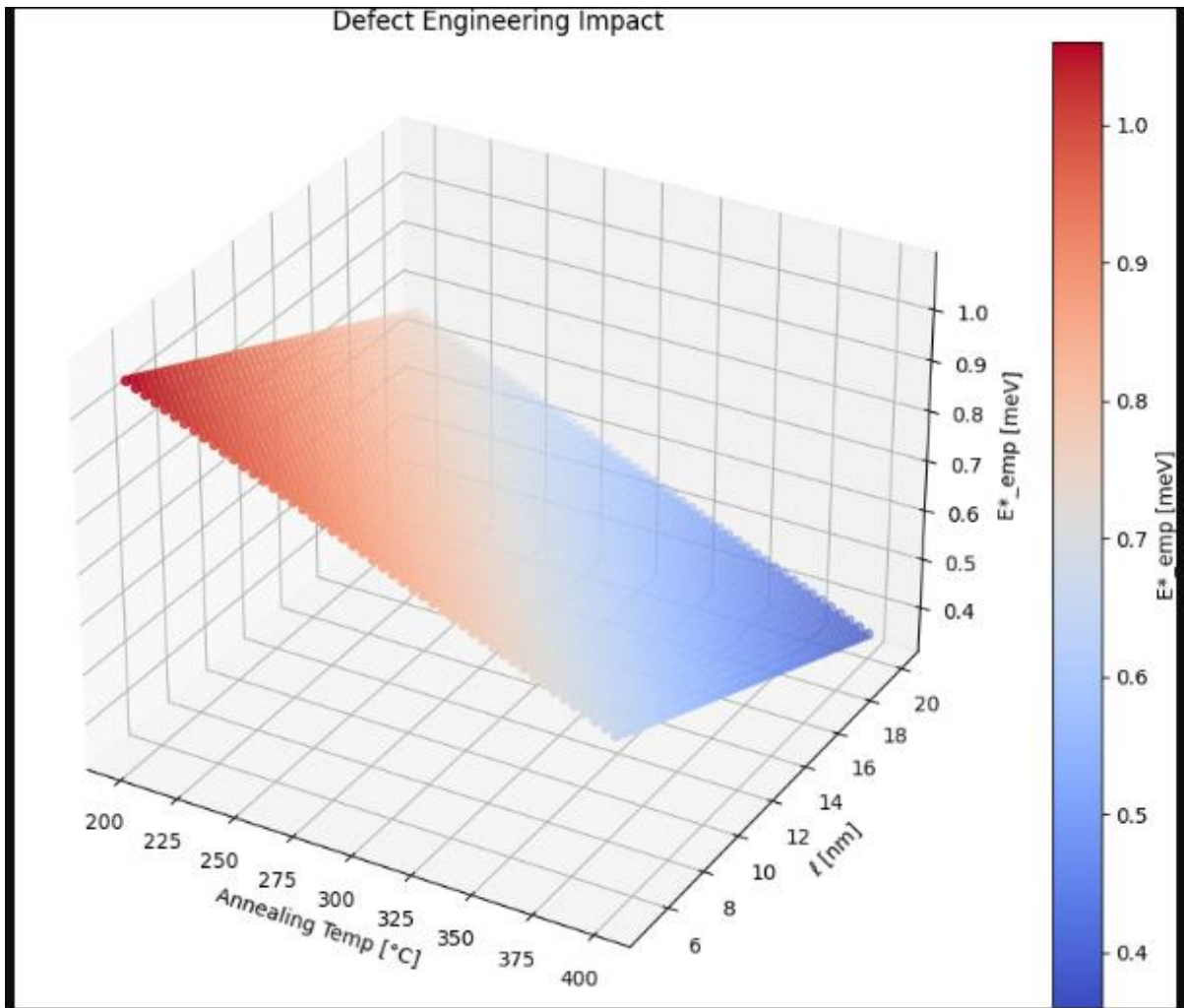
Volumetric plot:

X = Annealing Temp [°C]

Y =  $\ell$  [nm]

Z =  $E^*_emp$  [meV]

Isosurfaces: At  $J_e = 0.05, 0.1, 0.2$  MA/cm<sup>2</sup>



## 9. $R^2$ Correlation Matrix

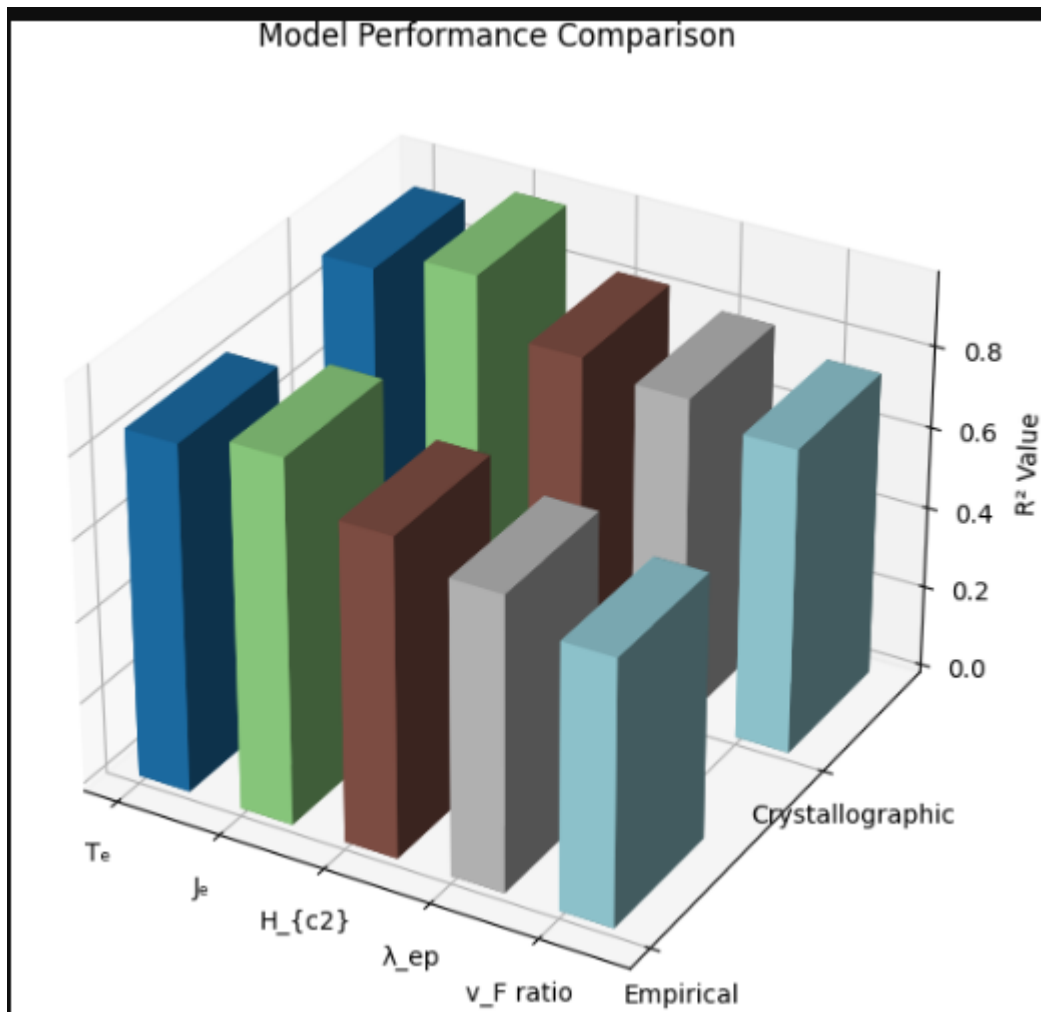
3D bar chart:

X-axis: Properties ( $T_e$ ,  $J_e$ ,  $H_{c2}$ ,  $\lambda_{ep}$ ,  $v_F$  ratio)

Y-axis: Model type (Empirical, Crystallographic)

Z-axis:  $R^2$  values (0-1)

Bar color: By property type



## 10. Synthesis Parameter Optimization

Parallel coordinates:

Axes:

1. Na deficiency (x)
2. Annealing time [h]
3. Texture factor (A)
4. Resulting  $E^*_{emp}$
5. Achieved  $T_e$

Lines: Colored by  $J_e$  performance

### Synthesis Parameter Optimization

